

## Hall Measurement System

The system can be used to find the following parameters of a film or the substrate

- Bulk/Sheet Concentration
- Mobility
- Resistivity
- Type of semiconductor (n-type or p-type)
- Conductivity
- Magneto-resistance



Temperature dependent hall measurement can be performed using this instrument. The temperature of the system can be varied from 80K to 350K. The system also provides the facility to perform I-V and I-R measurements along with graph plotting (room as well as temperature dependent).

### Limitations

- The sample size should not be greater than 1cm X 1cm
- The magnetic field of the system is fixed at 0.55 Tesla
- The current value ranges from 1nA to 20mA